Document Title

128Kx8 High Speed Static RAM(5V Operating), Revolutionary Pin out. Operated at Commercial and Industrial Temperature Range.

Revision History

Rev. No.	<u>History</u>			<u>Draft Data</u>	<u>Remark</u>
Rev. 0.0	Initial release with	n Preliminary.		Apr. 22th, 1995	Preliminary
Rev. 1.0	Release to final D 1.1. Delete Prelim			Feb. 29th, 1996	Final
Rev. 2.0	Update D.C parar 2.1. Update D.C p Items Icc Isb Isb1		Updated spec. (12/15/17/20ns part) 170/165/165/160mA 25mA 8mA	Jul. 16th, 1996	Final
Rev. 3.0	3.1. Add 32-Pin 3 3.2. Add Industria ters as Comr 3.2.1. Add Kl 3.2.2. Add or 3.2.3. Add th 3.3. Add the test of 3.4. Add timing dia	mperature Range parts and 00mil-SOJ Package. Il Temperature Range parts mercial Temperature Range M68002Al parts for Industriatering information. The condition for operating at condition for Voh1 with Vccagram to define twp as "(Tinges-Controlled)"	with the same parame- parts. al Temperature Range. Industrial Temp. Range. -5V±5% at 25°C	Jun. 2nd, 1997	Final
Rev. 4.0	4.1. Delete 17ns F	Part		Feb. 25th, 1998	Final

The attached data sheets are prepared and approved by SAMSUNG Electronics. SAMSUNG Electronics CO., LTD. reserve the right to change the specifications. SAMSUNG Electronics will evaluate and reply to your requests and questions on the parameters of this device. If you have any questions, please contact the SAMSUNG branch office near your office, call or contact Headquarters.



128K x 8 Bit High-Speed CMOS Static RAM

FEATURES

- Fast Access Time 12, 15, 20ns(Max.)
- Low Power Dissipation

Standby (TTL) : 25mA(Max.)

(CMOS): 8mA(Max.)

Operating KM681002A - 12: 170mA(Max.) KM681002A - 15: 165mA(Max.) KM681002A - 20: 160mA(Max.)

- Single 5.0V±10% Power Supply
- · TTL Compatible Inputs and Outputs
- I/O Compatible with 3.3V Device
- · Fully Static Operation
- No Clock or Refresh required
- · Three State Outputs
- Center Power/Ground Pin Configuration
- · Standard Pin Configuration

KM681002AJ: 32-SOJ-400 KM681002AT: 32-TSOP2-400F

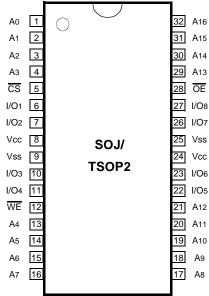
GENERAL DESCRIPTION

The KM681002A is a 1,048,576-bit high-speed Static Random Access Memory organized as 131,072 words by 8 bits. The KM681002A uses 8 common input and output lines and has an output enable pin which operates faster than address access time at read cycle. The device is fabricated using Samsung's advanced CMOS process and designed for high-speed circuit technology. It is particularly well suited for use in high-density high-speed system applications. The KM681002A is packaged in a 400mil 32-pin plastic SOJ or TSOP2 forward.

ORDERING INFORMATION

KM681002A -12/15/20	Commercial Temp.
KM681002AI -12/15/20	Industrial Temp.

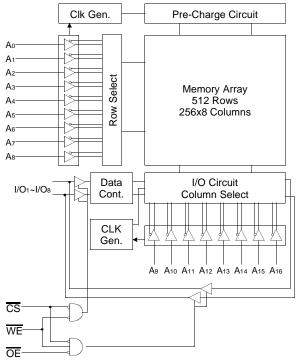
PIN CONFIGURATION(Top View)



Pin Name	Pin Function
A0 - A16	Address Inputs
WE	Write Enable
CS	Chip Select
ŌĒ	Output Enable
I/O1 ~ I/O8	Data Inputs/Outputs
Vcc	Power(+5.0V)
Vss	Ground

PIN FUNCTION

FUNCTIONAL BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS*

Parame	eter	Symbol	Rating	Unit
Voltage on Any Pin Relativ	ve to Vss	VIN, VOUT -0.5 to 7.0		V
Voltage on Vcc Supply Re	lative to Vss	Vcc -0.5 to 7.0		V
Power Dissipation		PD	1.0	W
Storage Temperature	Storage Temperature		-65 to 150	°C
Operating Temperature	Commercial	TA	0 to 70	°C
	Industrial	TA	-40 to 85	°C

^{*} Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

RECOMMENDED DC OPERATING CONDITIONS(TA=0 to 70°C)

Parameter	Symbol	Min	Тур	Max	Unit
Supply Voltage	Vcc	4.5	5.0	5.5	V
Ground	Vss	0	0	0	V
Input High Voltage	VIH	2.2	-	Vcc + 0.5**	V
Input Low Voltage	VIL	-0.5*	-	0.8	V

NOTE: The above parameters are also guaranteed at industrial temperature range.

DC AND OPERATING CHARACTERISTICS (TA=0 to 70°C, Vcc=5.0V±10%, unless otherwise specified)

Parameter	Symbol	Test Conditions		Min	Max	Unit
Input Leakage Current	lu	Vin=Vss to Vcc	-2	2	μΑ	
Output Leakage Current	llo	CS=VIH or OE=VIH or WE=VIL VOUT=Vss to Vcc	-2	2	μΑ	
Operating Current	Icc	Min. Cycle, 100% Duty	12ns	-	170	mA
		CS=VIL, VIN=VIH or VIL,	15ns	-	165	
		1001=0IIIA	20ns	-	160	
Standby Current	Isb	Min. Cycle, CS =Vін		-	25	mA
	ISB1	f=0MHz, $\overline{\text{CS}}$ ≥Vcc-0.2V, Vin≥Vcc-0.2V or Vin≤0.2V		-	8	mA
Output Low Voltage Level	Vol	IoL=8mA		-	0.4	V
Output High Voltage Level	Vон	IOH=-4mA		2.4	-	V
	VoH1*	Iон1=-0.1mA		-	3.95	V

NOTE: The above parameters are also guaranteed at industrial temperature range.

CAPACITANCE*(TA=25°C, f=1.0MHz)

Item	Symbol	Test Conditions	MIN	Max	Unit
Input/Output Capacitance	CI/O	VI/O=0V	-	8	pF
Input Capacitance	CIN	VIN=0V	-	6	pF

 $^{^{\}star}$ NOTE : Capacitance is sampled and not 100% tested.



^{*} V_{IL}(Min) = -2.0V a.c(Pulse Width≤10ns) for I≤20mA

^{**} VIH(Max) = Vcc + 2.0V a.c (Pulse Width≤10ns) for I≤20mA

^{*} Vcc=5.0V, Temp.=25°C

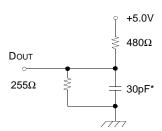
AC CHARACTERISTICS(TA=0 to 70°C, Vcc=5.0V±10%, unless otherwise noted.)

TEST CONDITIONS

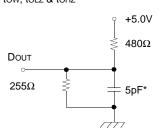
Parameter	Value
Input Pulse Levels	0V to 3V
Input Rise and Fall Times	3ns
Input and Output timing Reference Levels	1.5V
Output Loads	See below

NOTE: The above test conditions are also applied at industrial temperature range.





Output Loads(B) for thz, tLz, twhz, tow, toLz & toHz



* Including Scope and Jig Capacitance

READ CYCLE

Parameter	Symbol	KM6810	002A-12	KM6810	002A-15	KM6810	002A-20	Unit
Farameter	Syllibol	Min	Max	Min	Max	Min	Max	Ollit
Read Cycle Time	trc	12	-	15	-	20	-	ns
Address Access Time	taa	-	12	-	15	-	20	ns
Chip Select to Output	tco	-	12	-	15	-	20	ns
Output Enable to Valid Output	toe	-	6	-	7	-	9	ns
Chip Enable to Low-Z Output	tLZ	3	-	3	-	3	-	ns
Output Enable to Low-Z Output	toLz	0	-	0	-	0	-	ns
Chip Disable to High-Z Output	tHZ	0	6	0	7	0	9	ns
Output Disable to High-Z Output	tonz	0	6	0	7	0	9	ns
Output Hold from Address Change	tон	3	-	3	-	3	-	ns
Chip Selection to Power Up Time	tpu	0	-	0	-	0	-	ns
Chip Selection to Power DownTime	tPD	ı	12	-	15	-	20	ns

 $\ensuremath{\mathsf{NOTE}}$: The above parameters are also guaranteed at industrial temperature range.

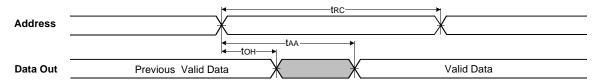
WRITE CYCLE

Davamatav	Cumbal	KM6810	002A-12	KM6810	02A-15 KM681002A-		002A-20	
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit
Write Cycle Time	twc	12	-	15	-	20	-	ns
Chip Select to End of Write	tcw	8	-	10	-	12	-	ns
Address Set-up Time	tas	0	-	0	-	0	-	ns
Address Valid to End of Write	taw	8	-	10	-	12	-	ns
Write Pulse Width(OE High)	twp	8	-	10	-	12	-	ns
Write Pulse Width(OE Low)	tWP1	12	-	15	-	20	-	ns
Write Recovery Time	twr	0	-	0	-	0	-	ns
Write to Output High-Z	twnz	0	6	0	7	0	9	ns
Data to Write Time Overlap	tow	6	-	7	-	9	-	ns
Data Hold from Write Time	tDH	0	-	0	-	0	-	ns
End Write to Output Low-Z	tow	3	-	3	-	3	-	ns

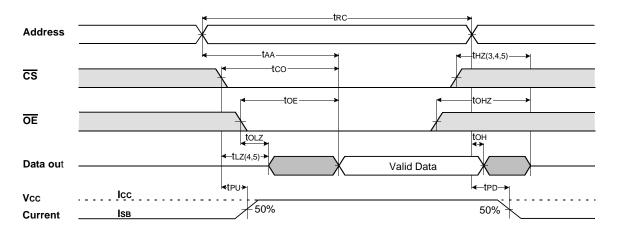
NOTE: The above parameters are also guaranteed at industrial temperature range.

TIMMING DIAGRAMS

TIMING WAVEFORM OF READ CYCLE(1) (Address Controlled, $\overline{CS} = \overline{OE} = V_{IL}$, $\overline{WE} = V_{IH}$)



TIMING WAVEFORM OF READ CYCLE(2) (WE=VIH)

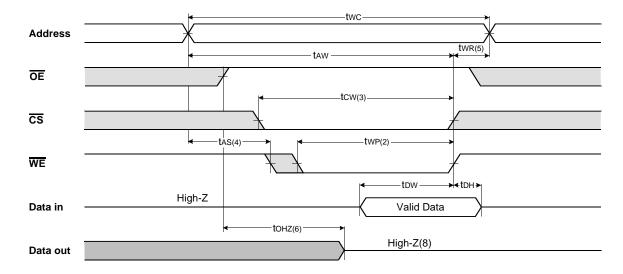


NOTES(READ CYCLE)

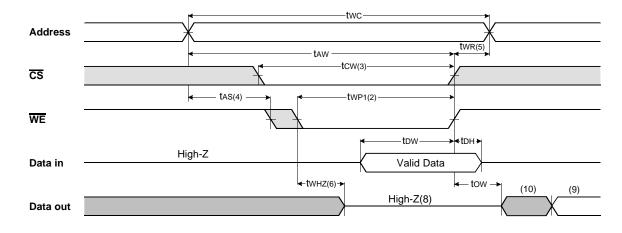
- 1. WE is high for read cycle.
- 2. All read cycle timing is referenced from the last valid address to the first transition address.
- 3. tнz and tонz are defined as the time at which the outputs achieve the open circuit condition and are not referenced to Voн or
- 4. At any given temperature and voltage condition, thz(Max.) is less than tLz(Min.) both for a given device and from device to device.
- 5. Transition is measured ±200mV from steady state voltage with Load(B). This parameter is sampled and not 100% tested.
- 6. Device is continuously selected with CS=V_{IL}

 7. Address valid prior to coincident with CS transition low.
- 8. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycle.

TIMING WAVEFORM OF WRITE CYCLE(1) (OE= Clock)

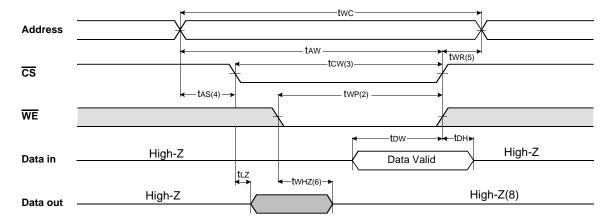


TIMING WAVEFORM OF WRITE CYCLE(2) (OE=Low Fixed)





TIMING WAVEFORM OF WRITE CYCLE(3) (CS = Controlled)



NOTES(WRITE CYCLE)

- 1. All write cycle timing is referenced from the last valid address to the first transition address.

 2. A write occurs during the overlap of <u>a low CS</u> and WE. A write begins at the latest transition CS going low and WE going low A write ends at the earliest transition \overline{CS} going high or \overline{WE} going high. twp is measured from the beginning of write to the end of
- 3. tcw is measured from the later of $\overline{\text{CS}}$ going low to end of write.
- 4. tas is measured from the address valid to the beginning of write.
- 5. twn is measured from the end of write to the address change. twn applied in case a write ends as $\overline{\text{CS}}$ or $\overline{\text{WE}}$ going high.
- 6. If $\overline{\text{OE}}$, $\overline{\text{CS}}$ and $\overline{\text{WE}}$ are in the Read Mode during this period, the I/O pins are in the output low-Z state. Inputs of opposite phase of the output must not be applied because bus contention can occur.
- 7. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycle.

 8. If CS goes low simultaneously with WE going or after WE going low, the outputs remain high impedance state.

 9. Dout is the read data of the new address.

- 10. When $\overline{\text{CS}}$ is low: I/O pins are in the output state. The input signals in the opposite phase leading to the output should not be applied.

FUNCTIONAL DESCRIPTION

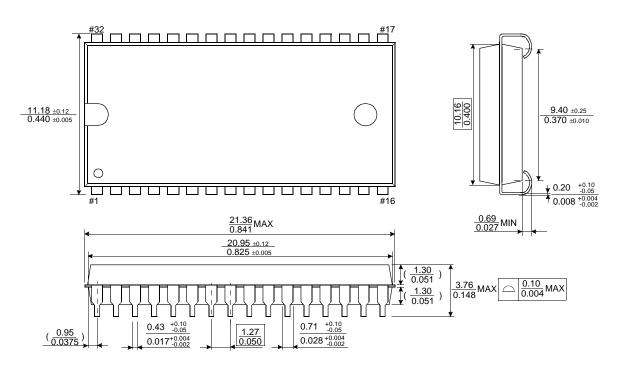
CS	WE	ŌĒ	Mode	I/O Pin	Supply Current
Н	X	X*	Not Select	High-Z	ISB, ISB1
L	Н	Н	Output Disable	High-Z	Icc
L	Н	L	Read	Dout	Icc
L	L	Х	Write	DIN	Icc

^{*} NOTE : X means Don't Care.

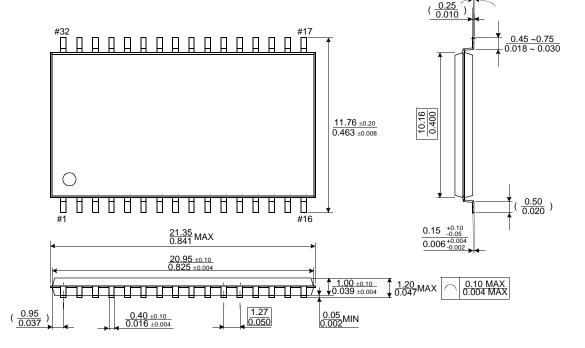


PACKAGE DIMENSIONS

32-SOJ-400 Units:millimeters/Inches



32-TSOP2-400F Units:millimeters/Inches



PACKAGE DIMENSIONS

